

39/589514

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S/N Filed Herewith

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	GIGLIO et al.	Examiner:	Unknown
Serial No.:	Filed Herewith	Group Art Unit:	Unknown
Filed:	August 15, 2006	Docket No.:	09728.0389USWO
Title:	A METHOD FOR MEASURING PROPERTIES OF PARTICLES BY MEANS OF INTERFERENCE FRINGE ANALYSIS AND CORRESPONDING APPARATUS		

CERTIFICATE UNDER 37 CFR 1.10:

"Express Mail" mailing label number: EV 840126496 US
Date of Deposit: August 15, 2006

I hereby certify that this paper or fee is being deposited with the U.S. Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Mail Stop PCT, Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450.

By: _____

Name: John J. Burke

INFORMATION DISCLOSURE STATEMENT (37 C.F.R. § 1.97(b))

Mail Stop PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner. Enclosed for the Examiner's information is a copy of the International Search Report. At least some of the references were recently cited in an International Search Report mailed July 14, 2005.

This statement should be considered because it is submitted within three months of the filing date of the above-identified application, which is not an application under 37 C.F.R. § 1.53(d). Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

A copy of any foreign patent document or "Other Document" listed on the Form 1449 is enclosed, in accordance with 37 C.F.R. § 1.98(a)(2). Because this application was filed after June 30, 2003, copies of the U.S. Patents and U.S. patent publications listed on the enclosed Form 1449 are not provided.

No representation is made that a reference is "prior art" within the meaning of 35 U.S.C. §§ 102 and 103 and Applicants reserve the right, pursuant to 37 C.F.R. § 1.131 or otherwise, to establish that the reference(s) are not "prior art." Moreover, Applicants do not represent that a reference has been thoroughly reviewed or that any relevance of any portion of a reference is intended.

Consideration of the items listed is respectfully requested. Pursuant to the provisions of M.P.E.P. 609, it is requested that the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

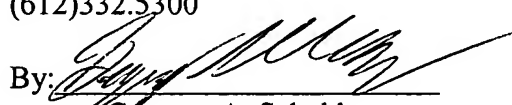
Please charge any additional fees or credit any overpayment to Deposit Account No. 13-2725.



Dated: August 15, 2006

Respectfully submitted,

MERCHANT & GOULD P.C.
P.O. Box 2903
Minneapolis, MN 55402-0903
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By: 
Gregory A. Sebald
Reg. No.: 33,280

GAS/mkc

Date Mailed: August 15, 2006

Sheet 1 of 1

FORM 1449* INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION (Use several sheets if necessary)	Docket Number: 09728.0389USWO	Application Number: Filed Herewith: 097589514
	Applicant: GIGLIO et al.	
	Filing Date: August 15, 2006	Group Art Unit: Unknown

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,327,217	7/1994	Kanai et al.			

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	02/103332 A2	12/2002	WIPO				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
		Brogioli, D. et al. "Heterodyne near-field scattering,: APPLIED PHYSICS LETTERS, 81(22): 4109-4111, November 25, 2002
		Glover, A.R. et al. "Interferometric laser imaging for droplet sizing: a method for droplet-size measurement in sparse spray systems," APPLIED OPTICS, 34(36): 8409-8421, December 20, 1995
		Kreuzer, H.J. et al. "Digital in-line holography," EUROPHYSICS NEWS, 34(2), March/April 2003
		Dubois, F. et al. "Pattern Recognition with a Digital Holographic Microscope Working in Partially Coherent Illumination," APPLIED OPTICS, 41(20): 4108-4119, July 10, 2002

23552
PATENT TRADEMARK OFFICE

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.	